**Product data sheet** 

# 1. General description

Planar passivated high commutation three quadrant triac in a SOT78 (TO-220AB) plastic package. This "series E" triac balances the requirements of commutation performance and gate sensitivity and is intended for interfacing with low power drivers including microcontrollers.

### 2. Features and benefits

- · 3Q technology for improved noise immunity
- · Direct interfacing with low power drivers and microcontrollers
- Good immunity to false turn-on by dV/dt
- · High commutation capability with sensitive gate
- High voltage capability
- Planar passivated for voltage ruggedness and reliability
- Sensitive gate for easy logic level triggering
- · Triggering in three quadrants only

## 3. Applications

- Electronic thermostats (heating and cooling)
- Motor controls e.g. washing machines and vacuum cleaners
- Refrigeration and air-conditioner compressor controls

### 4. Quick reference data

Table 1. Quick reference data

Parameter	Conditions		Min	Тур	Max	Unit
repetitive peak off- state voltage			-	-	600	V
RMS on-state current	full sine wave; $T_{mb} \le 106 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3		-	-	10	A
non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 20 \text{ ms}$ ; Fig. 4; Fig. 5		-	-	85	A
	full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 16.7 \text{ ms}$		-	-	93	A
junction temperature			-	-	125	°C
Static characteristics						
gate trigger current	V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2+ G+; T <sub>j</sub> = 25 °C; <u>Fig. 7</u>		0.5	-	10	mA
	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$		0.5	-	10	mA
	repetitive peak off- state voltage  RMS on-state current  non-repetitive peak on- state current  junction temperature	repetitive peak off-state voltage $ \begin{array}{ll} \text{RMS on-state current} & \text{full sine wave; $T_{mb} \leq 106 \ ^{\circ}\text{C; } \underline{\text{Fig. 1;}} \\ \hline \text{Fig. 2; Fig. 3} \\ \hline \text{non-repetitive peak on-state current} & \text{full sine wave; $T_{j(init)} = 25 \ ^{\circ}\text{C;}$} \\ \hline t_p = 20 \ \text{ms; } \underline{\text{Fig. 4; Fig. 5}} \\ \hline \text{full sine wave; $T_{j(init)} = 25 \ ^{\circ}\text{C;}$} \\ \hline t_p = 16.7 \ \text{ms} \\ \hline \text{junction temperature} \\ \hline \\ \textbf{gate trigger current} & V_D = 12 \ \text{V; } I_T = 0.1 \ \text{A; } T2 + G+; \\ \hline T_j = 25 \ ^{\circ}\text{C; } \underline{\text{Fig. 7}} \\ \hline V_D = 12 \ \text{V; } I_T = 0.1 \ \text{A; } T2 + G-; \\ \hline \end{array} $	repetitive peak off-state voltage $ \begin{array}{ll} \text{RMS on-state current} & \text{full sine wave; $T_{mb} \leq 106 \ ^{\circ}\text{C; } \underline{\text{Fig. 1;}} \\ \hline \text{Fig. 2; Fig. 3} \\ \hline \text{non-repetitive peak on-state current} & \text{full sine wave; $T_{j(init)} = 25 \ ^{\circ}\text{C;}$} \\ \hline t_p = 20 \ \text{ms; } \underline{\text{Fig. 4; Fig. 5}} \\ \hline \text{full sine wave; $T_{j(init)} = 25 \ ^{\circ}\text{C;}$} \\ \hline t_p = 16.7 \ \text{ms} \\ \hline \text{junction temperature} \\ \hline \\ \textbf{gate trigger current} & V_D = 12 \ \text{V; } I_T = 0.1 \ \text{A; } T2 + G+; \\ \hline T_j = 25 \ ^{\circ}\text{C; } \underline{\text{Fig. 7}} \\ \hline V_D = 12 \ \text{V; } I_T = 0.1 \ \text{A; } T2 + G-; \\ \hline \end{array} $	repetitive peak off-state voltage $ \begin{array}{c} \text{RMS on-state current} & \text{full sine wave; $T_{mb} \leq 106 \ ^{\circ}\text{C; } \underline{\text{Fig. 1;}} \\ \text{Fig. 2; Fig. 3} & - \\ \text{non-repetitive peak on-state current} & \text{full sine wave; $T_{j(init)} = 25 \ ^{\circ}\text{C;}$} \\ \text{t}_p = 20 \ \text{ms; } \underline{\text{Fig. 4; Fig. 5}} & - \\ \text{full sine wave; $T_{j(init)} = 25 \ ^{\circ}\text{C;}$} \\ \text{full sine wave; $T_{j(init)} = 25 \ ^{\circ}\text{C;}$} \\ \text{junction temperature} & - \\ \\ \textbf{gate trigger current} & V_D = 12 \ \text{V; } I_T = 0.1 \ \text{A; } T2 + G+; \\ T_j = 25 \ ^{\circ}\text{C; } \underline{\text{Fig. 7}} \\ V_D = 12 \ \text{V; } I_T = 0.1 \ \text{A; } T2 + G-; \\ \end{array} $	repetitive peak off-state voltage $ \begin{array}{ccccccccccccccccccccccccccccccccccc$	repetitive peak off-state voltage $ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$	0.5	-	10	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	15	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 12 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.25	1.5	V
Dynamic ch	naracteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 402 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	50	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 20 V/µs; (snubberless condition); gate open circuit	2	-	-	A/ms
		$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 10 V/ $\mu$ s; gate open circuit	3	-	-	A/ms
		$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit	6	-	-	A/ms

# 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1	mb	T2
2	T2	main terminal 2	<b>├</b>	G sym051
3	G	gate		symosi
mb	T2	mounting base; main terminal 2	1 2 3 TO-220AB (SOT78)	
			TO-220AB (SOT78)	

# 6. Ordering information

**Table 3. Ordering information** 

Type number	Package	ackage				
	Name	Description	Version			
BTA310-600E	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78			

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# 7. Limiting values

## **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	600	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{mb} \le 106 ^{\circ}\text{C}$ ; $\overline{\text{Fig. 1}}$ ; $\overline{\text{Fig. 2}}$ ; $\overline{\text{Fig. 3}}$	-	10	Α
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms; Fig. 4; Fig. 5	-	85	Α
		full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 16.7 ms	-	93	Α
I <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; SIN	-	36.1	A²s
dl <sub>T</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 0.2 A	-	100	A/µs
I <sub>GM</sub>	peak gate current		-	2	Α
$P_{GM}$	peak gate power		-	5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.5	W
T <sub>stg</sub>	storage temperature		-40	150	°C
T <sub>j</sub>	junction temperature		-	125	°C

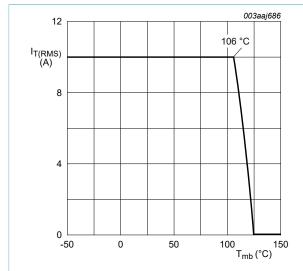


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

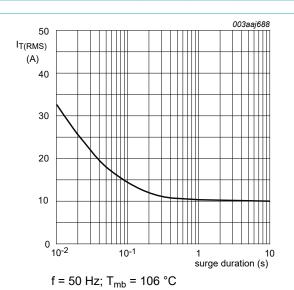


Fig. 2. RMS on-state current as a function of surge duration; maximum values

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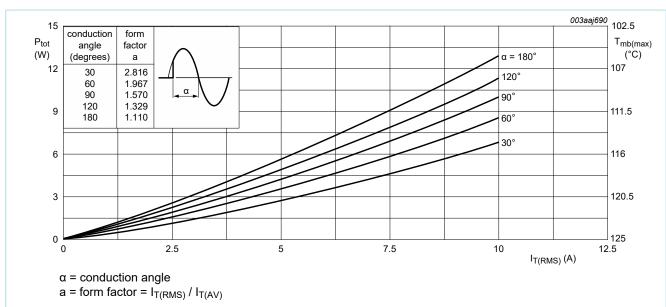


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

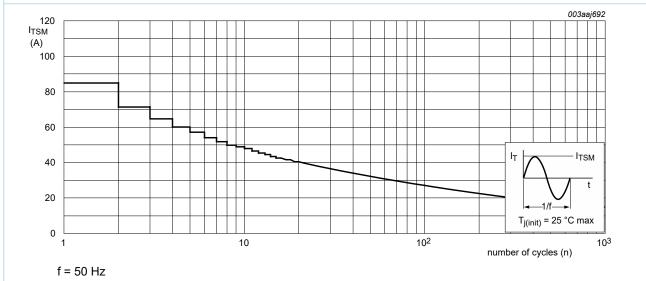
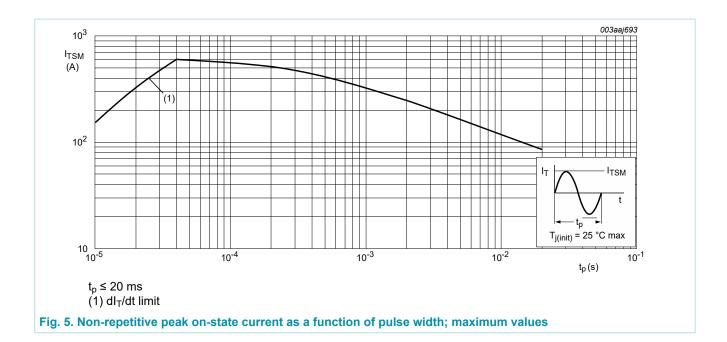


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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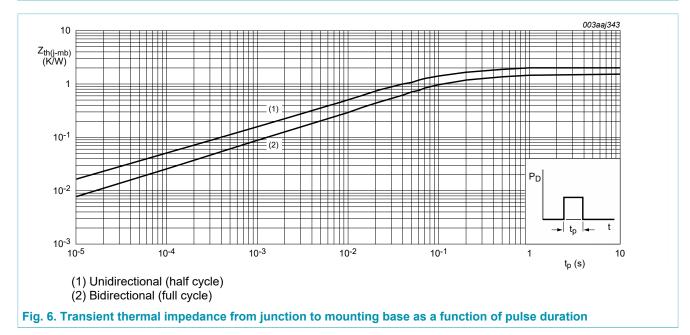


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## 8. Thermal characteristics

**Table 5. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance	full cycle; Fig. 6	-	-	1.5	K/W
	from junction to mounting base	half cycle; Fig. 6	-	-	2	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air	in free air	-	60	-	K/W



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## 9. Characteristics

### **Table 6. Characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$	0.5	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$	0.5	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 7$	0.5	-	10	mA
lL	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	25	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	30	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$	-	-	25	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	15	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 12 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.25	1.5	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.7	1	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 ^{\circ}\text{C};$ Fig. 11	0.25	0.4	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 600 V; T <sub>j</sub> = 125 °C	-	0.1	0.5	mA
Dynamic cl	haracteristics		·			
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 402 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	50	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 20 V/µs; (snubberless condition); gate open circuit	2	-	-	A/ms
		$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 10 V/µs; gate open circuit	3	-	-	A/ms
		$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit	6	-	-	A/ms

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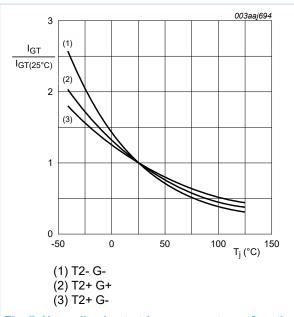


Fig. 7. Normalized gate trigger current as a function of junction temperature

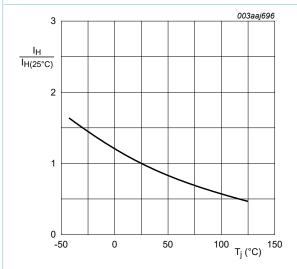


Fig. 9. Normalized holding current as a function of junction temperature

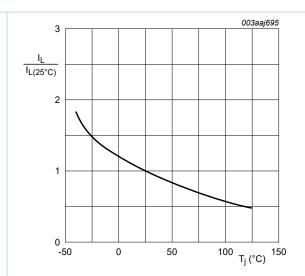
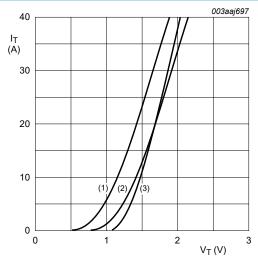


Fig. 8. Normalized latching current as a function of junction temperature



 $V_o$  = 1.103 V;  $R_s$  = 0.030 Ω (1)  $T_j$  = 125 °C; typical values (2)  $T_j$  = 125 °C; maximum values (3)  $T_j$  = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

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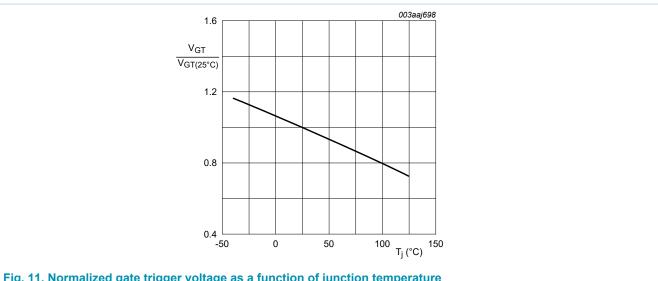
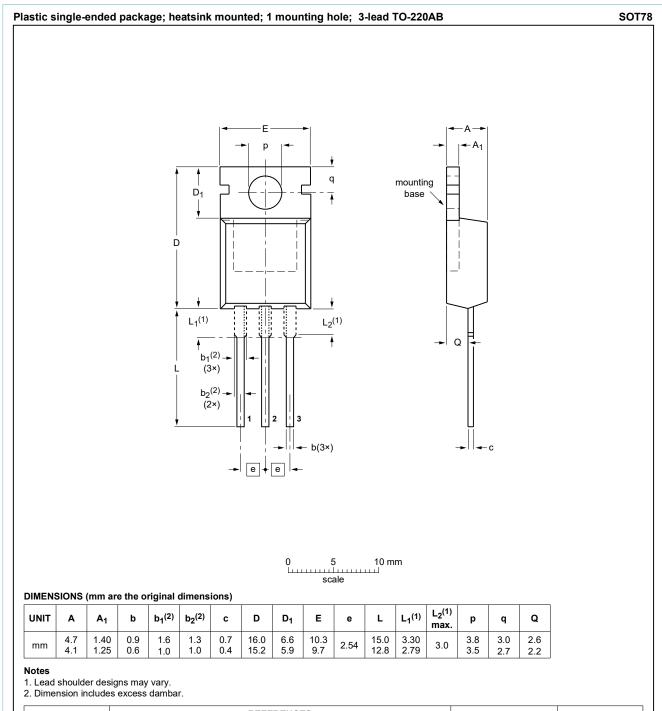


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

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# 10. Package outline



VERSION         IEC         JEDEC         JEITA         PROJECTION         ISSUE DATE           SOT78         3-lead TO-220AB         SC-46         \$\frac{08-04-23}{08-06-13}\$         08-04-23-08-06-13	OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
1  SO1/8  1  2  Iood TO 2200B  SC-46  1  Iood TO 2200B  SC-46  Iood TO 2200B  SC-46  Iood TO 2200B  Iood TO 2200	VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
	SOT78		3-lead TO-220AB	SC-46		

Fig. 12. Package outline TO-220AB (SOT78)

**3Q Hi-Com Triac** 

## 11. Legal information

#### **Data sheet status**

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
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For more information, please visit: http://www.ween-semi.com
For sales office addresses, please send an email to: salesaddresses@ween-semi.com
Date of release: 15 September 2018

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